MA3X198 (MA198)

Silicon epitaxial planar type

For wave detection

Features

- Two elements contained in one package, allowing high-density mounting
- Soft recovery characteristic ($t_{rr} = 100 \text{ ns}$)

ADSolute Maximum Hattings $T_a = 25 \text{ C}$							
Parameter		Symbol	Rating	Unit			
Reverse voltage		V _R	40	V			
Repetitive peak reverse voltage		V _{RRM}	40	V			
Forward current	Single	I _{F(AV)}	100	mA			
(Average)	Series		75				
Repetitive peak	Single	I _{FRM}	225	mA			
forward current	Series		170				
Non-repetitive peak	Single	I _{FSM}	500	mA			
forward surge current*	Series		325				
Junction temperature		Tj	150	°C			
Storage temperature		T _{stg}	-55 to +150	Sec 6			
				N . N			

Absolute Maximum Ratings $T_a = 25^{\circ}$



- Code
- Mini3-G1
- Pin Name
 - 1: Anode 1
 - 2: Cathode 2
 - 3: Cathode 1, Anode 2
- Marking Symbol: M2F

Internal Connection



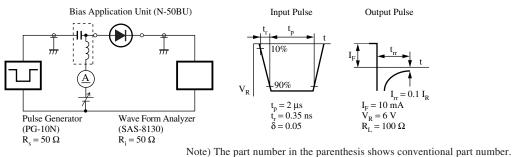
Note) *: t = 1 s

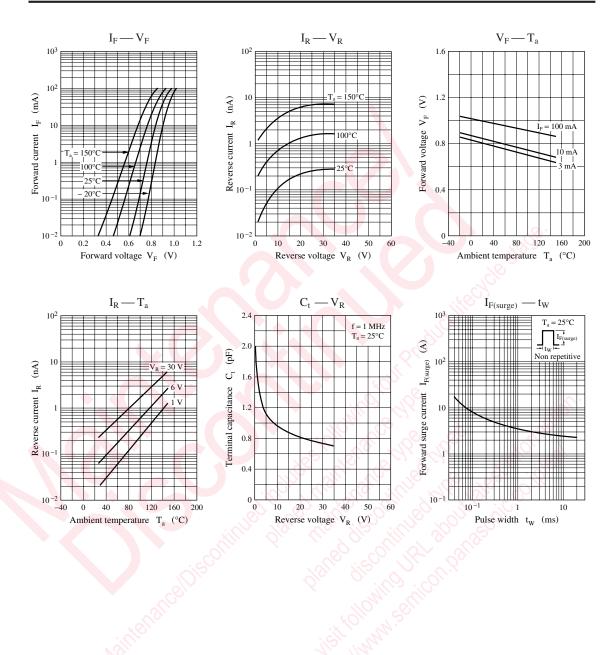
Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Forward voltage	V _{F1}	$I_{\rm F} = 100 \mu{\rm A}$	0.65		0.72	V
	V _{F2}	I _F = 100 mA	0.7		1.2	V
Reverse current	I _R	$V_R = 40 V$			10	nA
Terminal capacitance	Ct	$V_R = 6 V, f = 1 MHz$		1.0	2.0	pF
Reverse recovery time*	t _{rr}	$I_{\rm F} = 10 \text{ mA}, V_{\rm R} = 6 \text{ V}$			100	ns
a filter and the second s		$I_{rr} = 0.1 \ I_R, R_L = 100 \ \Omega$				

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7031 measuring methods for diodes.

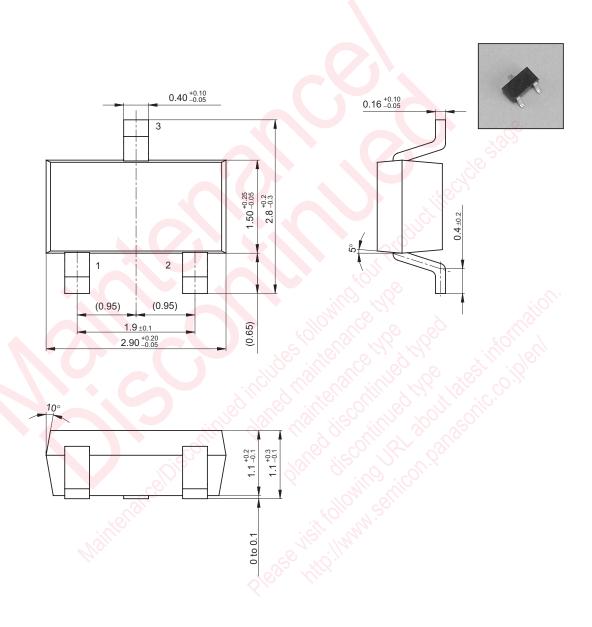
- 2. Absolute frequency of input and output is 10 MHz.
- 3. *: t_{rr} measurement circuit





Mini3-G1

Unit: mm



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